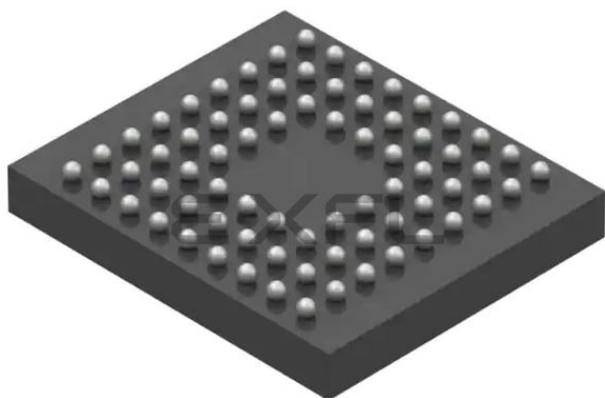




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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, MMC/SD, QSPI, SAI, SPI, SWPMI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, LCD, PWM, WDT
Number of I/O	57
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	128K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	72-UFBGA, WLCSP
Supplier Device Package	72-WLCSP (4.41x3.76)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l476jgy6tr

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Table 5. Functionalities depending on the working mode⁽¹⁾ (continued)

Peripheral	Run	Sleep	Low-power run	Low-power sleep	Stop 0/1		Stop 2		Standby		Shutdown		VBAT
					-	Wakeup capability	-	Wakeup capability	-	Wakeup capability	-	Wakeup capability	
LCD	O	O	O	O	O	O	O	O	-	-	-	-	-
USB OTG FS	O ⁽⁸⁾	O ⁽⁸⁾	-	-	-	O	-	-	-	-	-	-	-
USARTx (x=1,2,3,4,5)	O	O	O	O	O ⁽⁶⁾	O ⁽⁶⁾	-	-	-	-	-	-	-
Low-power UART (LPUART)	O	O	O	O	O ⁽⁶⁾	O ⁽⁶⁾	O ⁽⁶⁾	O ⁽⁶⁾	-	-	-	-	-
I2Cx (x=1,2)	O	O	O	O	O ⁽⁷⁾	O ⁽⁷⁾	-	-	-	-	-	-	-
I2C3	O	O	O	O	O ⁽⁷⁾	O ⁽⁷⁾	O ⁽⁷⁾	O ⁽⁷⁾	-	-	-	-	-
SPIx (x=1,2,3)	O	O	O	O	-	-	-	-	-	-	-	-	-
CAN	O	O	O	O	-	-	-	-	-	-	-	-	-
SDMMC1	O	O	O	O	-	-	-	-	-	-	-	-	-
SWPMI1	O	O	O	O	-	O	-	-	-	-	-	-	-
SAIx (x=1,2)	O	O	O	O	-	-	-	-	-	-	-	-	-
DFSDM	O	O	O	O	-	-	-	-	-	-	-	-	-
ADCx (x=1,2,3)	O	O	O	O	-	-	-	-	-	-	-	-	-
DACx (x=1,2)	O	O	O	O	O	-	-	-	-	-	-	-	-
VREFBUF	O	O	O	O	O	-	-	-	-	-	-	-	-
OPAMPx (x=1,2)	O	O	O	O	O	-	-	-	-	-	-	-	-
COMPx (x=1,2)	O	O	O	O	O	O	O	O	-	-	-	-	-
Temperature sensor	O	O	O	O	-	-	-	-	-	-	-	-	-
Timers (TIMx)	O	O	O	O	-	-	-	-	-	-	-	-	-
Low-power timer 1 (LPTIM1)	O	O	O	O	O	O	O	O	-	-	-	-	-
Low-power timer 2 (LPTIM2)	O	O	O	O	O	O	-	-	-	-	-	-	-
Independent watchdog (IWDG)	O	O	O	O	O	O	O	O	O	O	-	-	-
Window watchdog (WWDG)	O	O	O	O	-	-	-	-	-	-	-	-	-
SysTick timer	O	O	O	O	-	-	-	-	-	-	-	-	-
Touch sensing controller (TSC)	O	O	O	O	-	-	-	-	-	-	-	-	-

Table 6. STM32L476xx peripherals interconnect matrix (continued)

Interconnect source	Interconnect destination	Interconnect action	Run	Sleep	Low-power run	Low-power sleep	Stop 0 / Stop 1	Stop 2
GPIO	TIMx	External trigger	Y	Y	Y	Y	-	-
	LPTIMERx	External trigger	Y	Y	Y	Y	Y	Y ⁽¹⁾
	ADCx DACx DFSDM	Conversion external trigger	Y	Y	Y	Y	-	-

1. LPTIM1 only.

3.11 Clocks and startup

The clock controller (see [Figure 3](#)) distributes the clocks coming from different oscillators to the core and the peripherals. It also manages clock gating for low-power modes and ensures clock robustness. It features:

- **Clock prescaler:** to get the best trade-off between speed and current consumption, the clock frequency to the CPU and peripherals can be adjusted by a programmable prescaler
- **Safe clock switching:** clock sources can be changed safely on the fly in run mode through a configuration register.
- **Clock management:** to reduce power consumption, the clock controller can stop the clock to the core, individual peripherals or memory.
- **System clock source:** four different clock sources can be used to drive the master clock SYSCLK:
 - 4-48 MHz high-speed external crystal or ceramic resonator (HSE), that can supply a PLL. The HSE can also be configured in bypass mode for an external clock.
 - 16 MHz high-speed internal RC oscillator (HSI16), trimmable by software, that can supply a PLL
 - Multispeed internal RC oscillator (MSI), trimmable by software, able to generate 12 frequencies from 100 kHz to 48 MHz. When a 32.768 kHz clock source is available in the system (LSE), the MSI frequency can be automatically trimmed by hardware to reach better than $\pm 0.25\%$ accuracy. In this mode the MSI can feed the USB device, saving the need of an external high-speed crystal (HSE). The MSI can supply a PLL.
 - System PLL which can be fed by HSE, HSI16 or MSI, with a maximum frequency at 80 MHz.
- **Auxiliary clock source:** two ultralow-power clock sources that can be used to drive the LCD controller and the real-time clock:
 - 32.768 kHz low-speed external crystal (LSE), supporting four drive capability modes. The LSE can also be configured in bypass mode for an external clock.
 - 32 kHz low-speed internal RC (LSI), also used to drive the independent watchdog. The LSI clock accuracy is $\pm 5\%$ accuracy.
- **Peripheral clock sources:** Several peripherals (USB, SDMMC, RNG, SAI, USARTs, I2Cs, LPTimers, ADC, SWPMI) have their own independent clock whatever the system clock. Three PLLs, each having three independent outputs allowing the highest flexibility, can generate independent clocks for the ADC, the USB/SDMMC/RNG and the two SAIs.
- **Startup clock:** after reset, the microcontroller restarts by default with an internal 4 MHz clock (MSI). The prescaler ratio and clock source can be changed by the application program as soon as the code execution starts.
- **Clock security system (CSS):** this feature can be enabled by software. If a HSE clock failure occurs, the master clock is automatically switched to HSI16 and a software

3.25 Real-time clock (RTC) and backup registers

The RTC is an independent BCD timer/counter. It supports the following features:

- Calendar with subsecond, seconds, minutes, hours (12 or 24 format), week day, date, month, year, in BCD (binary-coded decimal) format.
- Automatic correction for 28, 29 (leap year), 30, and 31 days of the month.
- Two programmable alarms.
- On-the-fly correction from 1 to 32767 RTC clock pulses. This can be used to synchronize it with a master clock.
- Reference clock detection: a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision.
- Digital calibration circuit with 0.95 ppm resolution, to compensate for quartz crystal inaccuracy.
- Three anti-tamper detection pins with programmable filter.
- Timestamp feature which can be used to save the calendar content. This function can be triggered by an event on the timestamp pin, or by a tamper event, or by a switch to VBAT mode.
- 17-bit auto-reload wakeup timer (WUT) for periodic events with programmable resolution and period.

The RTC and the 32 backup registers are supplied through a switch that takes power either from the V_{DD} supply when present or from the VBAT pin.

The backup registers are 32-bit registers used to store 128 bytes of user application data when VDD power is not present. They are not reset by a system or power reset, or when the device wakes up from Standby or Shutdown mode.

The RTC clock sources can be:

- A 32.768 kHz external crystal (LSE)
- An external resonator or oscillator (LSE)
- The internal low power RC oscillator (LSI, with typical frequency of 32 kHz)
- The high-speed external clock (HSE) divided by 32.

The RTC is functional in VBAT mode and in all low-power modes when it is clocked by the LSE. When clocked by the LSI, the RTC is not functional in VBAT mode, but is functional in all low-power modes except Shutdown mode.

All RTC events (Alarm, WakeUp Timer, Timestamp or Tamper) can generate an interrupt and wakeup the device from the low-power modes.

The major features are:

- Combined Rx and Tx FIFO size of 1.25 KB with dynamic FIFO sizing
- Supports the session request protocol (SRP) and host negotiation protocol (HNP)
- 1 bidirectional control endpoint + 5 IN endpoints + 5 OUT endpoints
- 8 host channels with periodic OUT support
- HNP/SNP/IP inside (no need for any external resistor)
- Software configurable to OTG 1.3 and OTG 2.0 modes of operation
- OTG 2.0 Supports ADP (Attach detection Protocol)
- USB 2.0 LPM (Link Power Management) support
- Battery Charging Specification Revision 1.2 support
- Internal FS OTG PHY support

For OTG/Host modes, a power switch is needed in case bus-powered devices are connected.

3.35 Flexible static memory controller (FSMC)

The Flexible static memory controller (FSMC) includes two memory controllers:

- The NOR/PSRAM memory controller
- The NAND/memory controller

This memory controller is also named Flexible memory controller (FMC).

The main features of the FMC controller are the following:

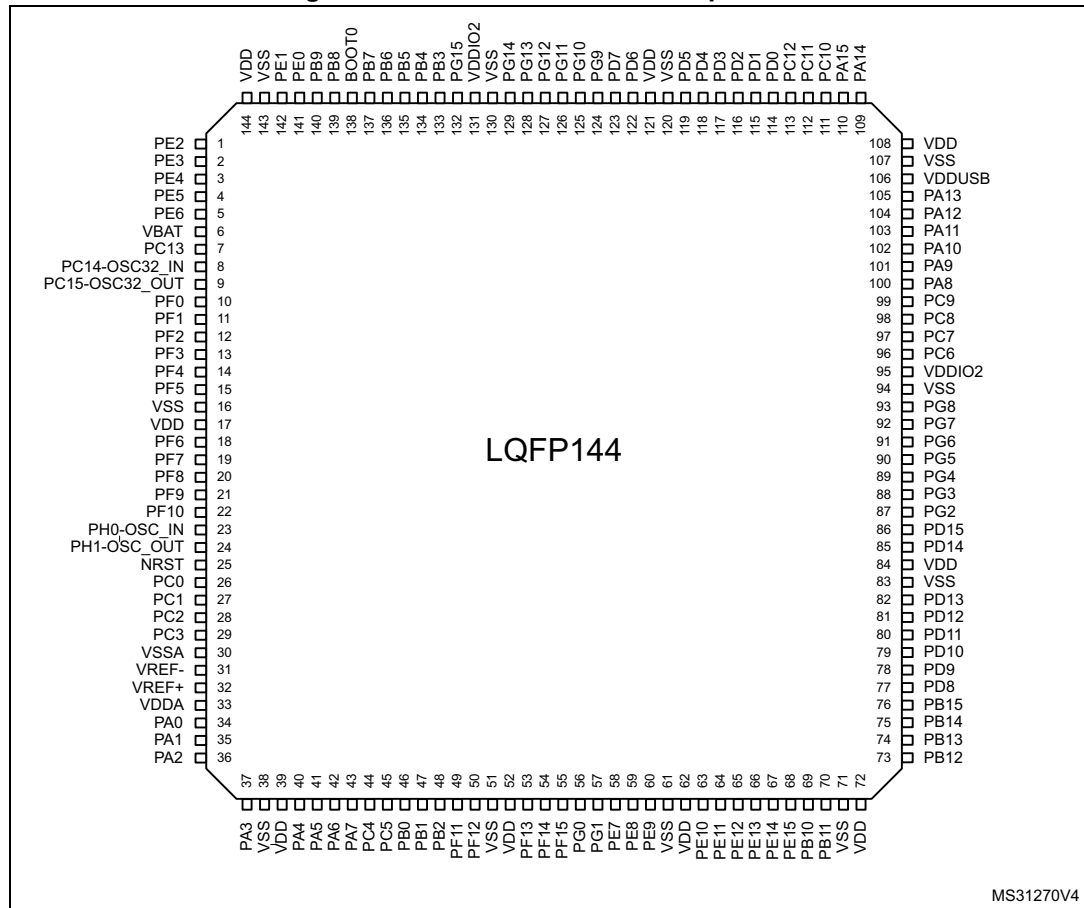
- Interface with static-memory mapped devices including:
 - Static random access memory (SRAM)
 - NOR Flash memory/OneNAND Flash memory
 - PSRAM (4 memory banks)
 - NAND Flash memory with ECC hardware to check up to 8 Kbyte of data
- 8-,16- bit data bus width
- Independent Chip Select control for each memory bank
- Independent configuration for each memory bank
- Write FIFO
- The Maximum FMC_CLK frequency for synchronous accesses is HCLK/2.

LCD parallel interface

The FMC can be configured to interface seamlessly with most graphic LCD controllers. It supports the Intel 8080 and Motorola 6800 modes, and is flexible enough to adapt to specific LCD interfaces. This LCD parallel interface capability makes it easy to build cost effective graphic applications using LCD modules with embedded controllers or high performance solutions using external controllers with dedicated acceleration.

4 Pinouts and pin description

Figure 4. STM32L476Zx LQFP144 pinout⁽¹⁾



1. The above figure shows the package top view.

Figure 7. STM32L476Mx WLCSP81 ballout⁽¹⁾

	1	2	3	4	5	6	7	8	9
A	VDDUSB	PA15	PD2	PG9	PG14	PB3	PB7	VSS	VDD
B	VSS	PA14	PC12	PG10	PG13	VDDIO2	PB6	PC13	VBAT
C	PA12	PA13	PC11	PG11	PG12	PB4	PB5	PC15-OSC32_OUT	PC14-OSC32_IN
D	PA11	PA10	PC10	PD5	PD6	PD7	BOOT0	PH1-OSC_OUT	PH0-OSC_IN
E	PC9	PA8	PA9	VDD	PD4	PE7	PB8	PB9	NRST
F	PC7	PC8	PC6	PD9	PD8	PE8	PC2	PC1	PC0
G	PB15	PB14	PB11	PA1	PA4	PA2	PC3	VREF+	VSSA/VREF-
H	PB12	PB13	PB10	PA7	PA6	PA5	PA3	PA0	VDDA
J	VDD	VSS	PB2	PB1	PB0	PC5	PC4	VDD	VSS

MSv38020V3

1. The above figure shows the package top view.

Figure 8. STM32L476Jx WLCSP72 ballout⁽¹⁾

	1	2	3	4	5	6	7	8	9
A	VDDUSB	PA15	PD2	PG9	PG14	PB3	PB7	VSS	VDD
B	VSS	PA14	PC12	PG10	PG13	VDDIO2	PB6	PC13	VBAT
C	PA12	PA13	PC11	PG11	PG12	PB4	PB5	PC15-OSC32_OUT	PC14-OSC32_IN
D	PA11	PA10	PC10	WLCSP72			BOOT0	PH1-OSC_OUT	PH0-OSC_IN
E	PC9	PA8	PA9				PB8	PB9	NRST
F	PC7	PC8	PC6				PC2	PC1	PC0
G	PB15	PB14	PB11	PA1	PA4	PA2	PC3	VREF+	VSSA/VREF-
H	PB12	PB13	PB10	PA7	PA6	PA5	PA3	PA0	VDDA
J	VDD	VSS	PB2	PB1	PB0	PC5	PC4	VDD	VSS

MSv35083V7

1. The above figure shows the package top view.

Table 15. STM32L476xxSTM32L476xx pin definitions (continued)

Pin Number						Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	WLCSP72	WLCSP81	LQFP100	UFPGA132	LQFP144					Alternate functions	Additional functions
59	A7	A7	93	B4	137	PB7	I/O	FT_flg	-	LPTIM1_IN2, TIM4_CH2, TIM8_BKIN, I2C1_SDA, DFSDM_CKIN5, USART1_RX, UART4_CTS, TSC_G2_IO4, LCD_SEG21, FMC_NL, TIM8_BKIN_COMP1, TIM17_CH1N, EVENTOUT	COMP2_INM, PVD_IN
60	D7	D7	94	A4	138	BOOT0	I	-	-	-	-
61	E7	E7	95	A3	139	PB8	I/O	FT_fl	-	TIM4_CH3, I2C1_SCL, DFSDM_DATIN6, CAN1_RX, LCD_SEG16, SDMMC1_D4, SAI1_MCLK_A, TIM16_CH1, EVENTOUT	-
62	E8	E8	96	B3	140	PB9	I/O	FT_fl	-	IR_OUT, TIM4_CH4, I2C1_SDA, SPI2_NSS, DFSDM_CKIN6, CAN1_TX, LCD_COM3, SDMMC1_D5, SAI1_FS_A, TIM17_CH1, EVENTOUT	-
-	-	-	97	C3	141	PE0	I/O	FT_I	-	TIM4_ETR, LCD_SEG36, FMC_NBL0, TIM16_CH1, EVENTOUT	-
-	-	-	98	A2	142	PE1	I/O	FT_I	-	LCD_SEG37, FMC_NBL1, TIM17_CH1, EVENTOUT	-
63	A8	A8	99	D3	143	VSS	S	-	-	-	-
64	A9	A9	100	C4	144	VDD	S	-	-	-	-

1. PC13, PC14 and PC15 are supplied through the power switch. Since the switch only sinks a limited amount of current (3 mA), the use of GPIOs PC13 to PC15 in output mode is limited:
 - The speed should not exceed 2 MHz with a maximum load of 30 pF
 - These GPIOs must not be used as current sources (e.g. to drive an LED).
2. After a Backup domain power-up, PC13, PC14 and PC15 operate as GPIOs. Their function then depends on the content of the RTC registers which are not reset by the system reset. For details on how to manage these GPIOs, refer to the Backup domain and RTC register descriptions in the RM0351 reference manual.
3. After reset, these pins are configured as JTAG/SW debug alternate functions, and the internal pull-up on PA15, PA13, PB4 pins and the internal pull-down on PA14 pin are activated.

Table 16. Alternate function AF0 to AF7 (for AF8 to AF15 see [Table 17](#))

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7
		SYS_AF	TIM1/TIM2/ TIM5/TIM8/ LPTIM1	TIM1/TIM2/ TIM3/TIM4/ TIM5	TIM8	I2C1/I2C2/I2C3	SPI1/SPI2	SPI3/DFSDM	USART1/ USART2/ USART3
Port A	PA0	-	TIM2_CH1	TIM5_CH1	TIM8_ETR	-	-	-	USART2_CTS
	PA1	-	TIM2_CH2	TIM5_CH2	-	-	-	-	USART2_RTS_ DE
	PA2	-	TIM2_CH3	TIM5_CH3	-	-	-	-	USART2_TX
	PA3	-	TIM2_CH4	TIM5_CH4	-	-	-	-	USART2_RX
	PA4	-	-	-	-	-	SPI1_NSS	SPI3_NSS	USART2_CK
	PA5	-	TIM2_CH1	TIM2_ETR	TIM8_CH1N	-	SPI1_SCK	-	-
	PA6	-	TIM1_BKIN	TIM3_CH1	TIM8_BKIN	-	SPI1_MISO	-	USART3_CTS
	PA7	-	TIM1_CH1N	TIM3_CH2	TIM8_CH1N	-	SPI1_MOSI	-	-
	PA8	MCO	TIM1_CH1	-	-	-	-	-	USART1_CK
	PA9	-	TIM1_CH2	-	-	-	-	-	USART1_TX
	PA10	-	TIM1_CH3	-	-	-	-	-	USART1_RX
	PA11	-	TIM1_CH4	TIM1_BKIN2	-	-	-	-	USART1_CTS
	PA12	-	TIM1_ETR	-	-	-	-	-	USART1_RTS_ DE
	PA13	JTMS-SWDIO	IR_OUT	-	-	-	-	-	-
	PA14	JTCK-SWCLK	-	-	-	-	-	-	-
	PA15	JTDI	TIM2_CH1	TIM2_ETR	-	-	SPI1_NSS	SPI3_NSS	-

Table 17. Alternate function AF8 to AF15 (for AF0 to AF7 see [Table 16](#))

Port		AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		UART4, UART5, LPUART1	CAN1, TSC	OTG_FS, QUADSPI	LCD	SDMMC1, COMP1, COMP2, FMC, SWPMI1	SAI1, SAI2	TIM2, TIM15, TIM16, TIM17, LPTIM2	EVENTOUT
Port A	PA0	UART4_TX	-	-	-	-	SAI1_EXTCLK	TIM2_ETR	EVENTOUT
	PA1	UART4_RX	-	-	LCD_SEG0	-	-	TIM15_CH1N	EVENTOUT
	PA2	-	-	-	LCD_SEG1	-	SAI2_EXTCLK	TIM15_CH1	EVENTOUT
	PA3	-	-	-	LCD_SEG2	-	-	TIM15_CH2	EVENTOUT
	PA4	-	-	-	-	-	SAI1_FS_B	LPTIM2_OUT	EVENTOUT
	PA5	-	-	-	-	-	-	LPTIM2_ETR	EVENTOUT
	PA6	-	-	QUADSPI_BK1_IO3	LCD_SEG3	TIM1_BKIN_ COMP2	TIM8_BKIN_ COMP2	TIM16_CH1	EVENTOUT
	PA7	-	-	QUADSPI_BK1_IO2	LCD_SEG4	-	-	TIM17_CH1	EVENTOUT
	PA8	-	-	OTG_FS_SOF	LCD_COM0	-	-	LPTIM2_OUT	EVENTOUT
	PA9	-	-	-	LCD_COM1	-	-	TIM15_BKIN	EVENTOUT
	PA10	-	-	OTG_FS_ID	LCD_COM2	-	-	TIM17_BKIN	EVENTOUT
	PA11	-	CAN1_RX	OTG_FS_DM	-	TIM1_BKIN2_ COMP1	-	-	EVENTOUT
	PA12	-	CAN1_TX	OTG_FS_DP	-	-	-	-	EVENTOUT
	PA13	-	-	OTG_FS_NOE	-	-	-	-	EVENTOUT
	PA14	-	-	-	-	-	-	-	EVENTOUT
	PA15	UART4_RTS_ DE	TSC_G3_IO1	-	LCD_SEG17	-	SAI2_FS_B	-	EVENTOUT

Table 36. Current consumption in Stop 0 mode

Symbol	Parameter	Conditions	TYP					MAX ⁽¹⁾					Unit
		V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD} (Stop 0)	Supply current in Stop 0 mode, RTC disabled	1.8 V	108	132	217	356	631	153	213	426	773	1461	μA
		2.4 V	110	134	219	358	634	158	218	431	778	1468	
		3 V	111	135	220	360	637	161	221	433	783	1476	
		3.6 V	113	137	222	363	642	166	226	438	791 ⁽²⁾	1488	

1. Guaranteed by characterization results, unless otherwise specified.

2. Guaranteed by test in production.

Table 64. Maximum ADC RAIN⁽¹⁾⁽²⁾ (continued)

Resolution	Sampling cycle @80 MHz	Sampling time [ns] @80 MHz	RAIN max (Ω)	
			Fast channels ⁽³⁾	Slow channels ⁽⁴⁾
6 bits	2.5	31.25	220	N/A
	6.5	81.25	560	330
	12.5	156.25	1200	1000
	24.5	306.25	2700	2200
	47.5	593.75	3900	3300
	92.5	1156.25	8200	6800
	247.5	3093.75	18000	15000
	640.5	8006.75	50000	50000

1. Guaranteed by design.
2. The I/O analog switch voltage booster is enable when $V_{DDA} < 2.4$ V (BOOSTEN = 1 in the SYSCFG_CFGR1 when $V_{DDA} < 2.4$ V). It is disable when $V_{DDA} \geq 2.4$ V.
3. Fast channels are: PC0, PC1, PC2, PC3, PA0, PA1.
4. Slow channels are: all ADC inputs except the fast channels.

Table 66. ADC accuracy - limited test conditions 2⁽¹⁾(2)(3)

Sym- bol	Parameter	Conditions ⁽⁴⁾		Min	Typ	Max	Unit
ET	Total unadjusted error	Single ended	Fast channel (max speed)	-	4	6.5	LSB
			Slow channel (max speed)	-	4	6.5	
		Differential	Fast channel (max speed)	-	3.5	5.5	
			Slow channel (max speed)	-	3.5	5.5	
EO	Offset error	Single ended	Fast channel (max speed)	-	1	4.5	
			Slow channel (max speed)	-	1	5	
		Differential	Fast channel (max speed)	-	1.5	3	
			Slow channel (max speed)	-	1.5	3	
EG	Gain error	Single ended	Fast channel (max speed)	-	2.5	6	
			Slow channel (max speed)	-	2.5	6	
		Differential	Fast channel (max speed)	-	2.5	3.5	
			Slow channel (max speed)	-	2.5	3.5	
ED	Differential linearity error	Single ended	Fast channel (max speed)	-	1	1.5	
			Slow channel (max speed)	-	1	1.5	
		Differential	Fast channel (max speed)	-	1	1.2	
			Slow channel (max speed)	-	1	1.2	
EL	Integral linearity error	Single ended	Fast channel (max speed)	-	1.5	3.5	
			Slow channel (max speed)	-	1.5	3.5	
		Differential	Fast channel (max speed)	-	1	3	
			Slow channel (max speed)	-	1	2.5	
ENOB	Effective number of bits	Single ended	Fast channel (max speed)	10	10.5	-	bits
			Slow channel (max speed)	10	10.5	-	
		Differential	Fast channel (max speed)	10.7	10.9	-	
			Slow channel (max speed)	10.7	10.9	-	
SINAD	Signal-to-noise and distortion ratio	Single ended	Fast channel (max speed)	62	65	-	dB
			Slow channel (max speed)	62	65	-	
		Differential	Fast channel (max speed)	66	67.4	-	
			Slow channel (max speed)	66	67.4	-	
SNR	Signal-to-noise ratio	Single ended	Fast channel (max speed)	64	66	-	
			Slow channel (max speed)	64	66	-	
		Differential	Fast channel (max speed)	66.5	68	-	
			Slow channel (max speed)	66.5	68	-	

Table 70. DAC accuracy⁽¹⁾ (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Gain	Gain error ⁽⁵⁾	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ	-	-	±0.5	%
		DAC output buffer OFF CL ≤ 50 pF, no RL	-	-	±0.5	
TUE	Total unadjusted error	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ	-	-	±30	LSB
		DAC output buffer OFF CL ≤ 50 pF, no RL	-	-	±12	
TUEcal	Total unadjusted error after calibration	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ	-	-	±23	LSB
SNR	Signal-to-noise ratio	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ 1 kHz, BW 500 kHz	-	71.2	-	dB
		DAC output buffer OFF CL ≤ 50 pF, no RL, 1 kHz BW 500 kHz	-	71.6	-	
THD	Total harmonic distortion	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ, 1 kHz	-	-78	-	dB
		DAC output buffer OFF CL ≤ 50 pF, no RL, 1 kHz	-	-79	-	
SINAD	Signal-to-noise and distortion ratio	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ, 1 kHz	-	70.4	-	dB
		DAC output buffer OFF CL ≤ 50 pF, no RL, 1 kHz	-	71	-	
ENOB	Effective number of bits	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ, 1 kHz	-	11.4	-	bits
		DAC output buffer OFF CL ≤ 50 pF, no RL, 1 kHz	-	11.5	-	

1. Guaranteed by design.
2. Difference between two consecutive codes - 1 LSB.
3. Difference between measured value at Code i and the value at Code i on a line drawn between Code 0 and last Code 4095.
4. Difference between the value measured at Code (0x001) and the ideal value.
5. Difference between ideal slope of the transfer function and measured slope computed from code 0x000 and 0xFF when buffer is OFF, and from code giving 0.2 V and (V_{REF+} - 0.2) V when buffer is ON.

Table 79. TIMx⁽¹⁾ characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
$t_{res(TIM)}$	Timer resolution time	-	1	-	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 80\text{ MHz}$	12.5	-	ns
f_{EXT}	Timer external clock frequency on CH1 to CH4	-	0	$f_{TIMxCLK}/2$	MHz
		$f_{TIMxCLK} = 80\text{ MHz}$	0	40	MHz
Res_{TIM}	Timer resolution	TIMx (except TIM2 and TIM5)	-	16	bit
		TIM2 and TIM5	-	32	
$t_{COUNTER}$	16-bit counter clock period	-	1	65536	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 80\text{ MHz}$	0.0125	819.2	μs
t_{MAX_COUNT}	Maximum possible count with 32-bit counter	-	-	65536×65536	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 80\text{ MHz}$	-	53.68	s

1. TIMx is used as a general term in which x stands for 1,2,3,4,5,6,7,8,15,16 or 17.

Table 80. IWDG min/max timeout period at 32 kHz (LSI)⁽¹⁾

Prescaler divider	PR[2:0] bits	Min timeout RL[11:0]=0x000	Max timeout RL[11:0]=0xFFFF	Unit
/4	0	0.125	512	ms
/8	1	0.250	1024	
/16	2	0.500	2048	
/32	3	1.0	4096	
/64	4	2.0	8192	
/128	5	4.0	16384	
/256	6 or 7	8.0	32768	

1. The exact timings still depend on the phasing of the APB interface clock versus the LSI clock so that there is always a full RC period of uncertainty.

Table 81. WWDG min/max timeout value at 80 MHz (PCLK)

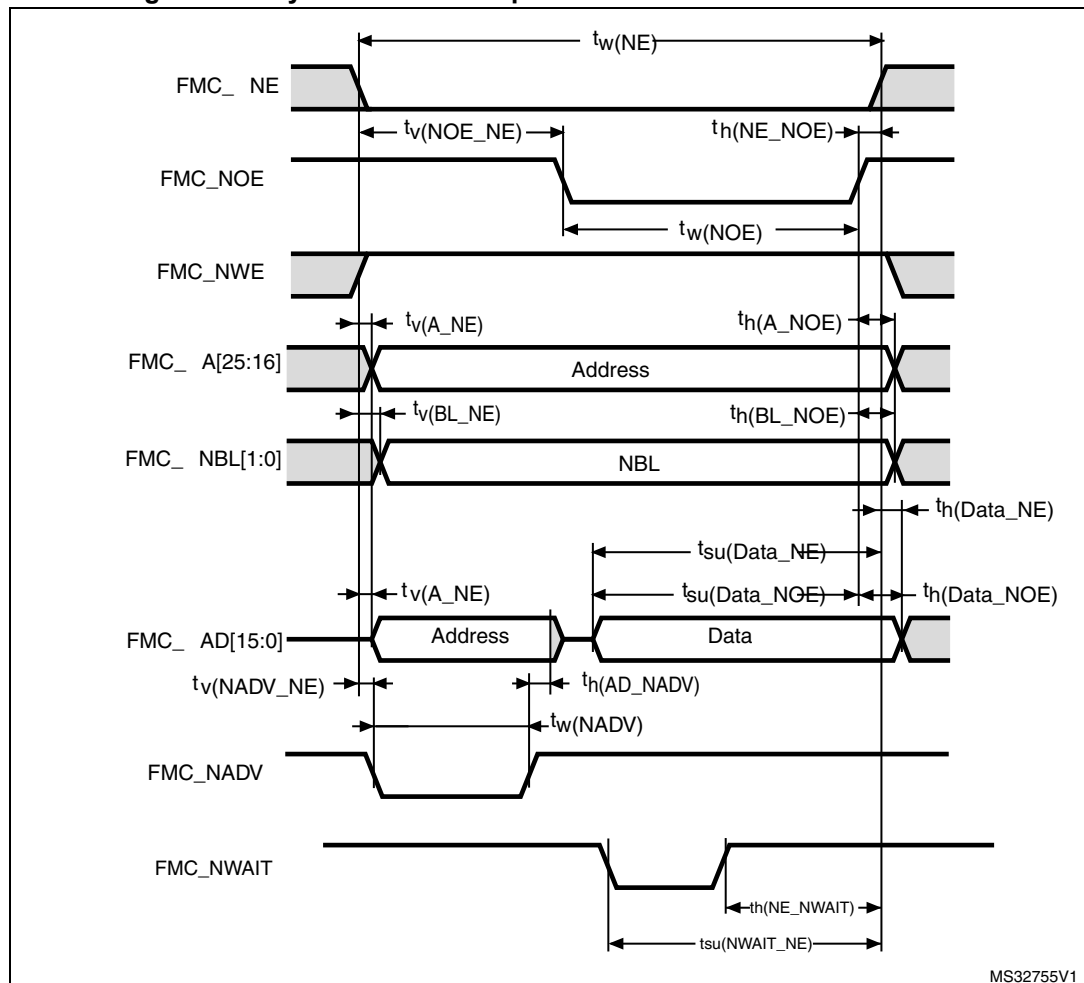
Prescaler	WDGTB	Min timeout value	Max timeout value	Unit
1	0	0.0512	3.2768	ms
2	1	0.1024	6.5536	
4	2	0.2048	13.1072	
8	3	0.4096	26.2144	

Table 93. Asynchronous non-multiplexed SRAM/PSRAM/NOR write-NWAIT timings⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$8T_{HCLK}+0.5$	$8T_{HCLK}+0.5$	ns
$t_{w(NWE)}$	FMC_NWE low time	$6T_{HCLK}-0.5$	$6T_{HCLK}+0.5$	
$t_{su(NWAIT_NE)}$	FMC_NWAIT valid before FMC_NEx high	$6T_{HCLK}+2$	-	
$t_{h(NE_NWAIT)}$	FMC_NEx hold time after FMC_NWAIT invalid	$4T_{HCLK}+2$	-	

1. CL = 30 pF.

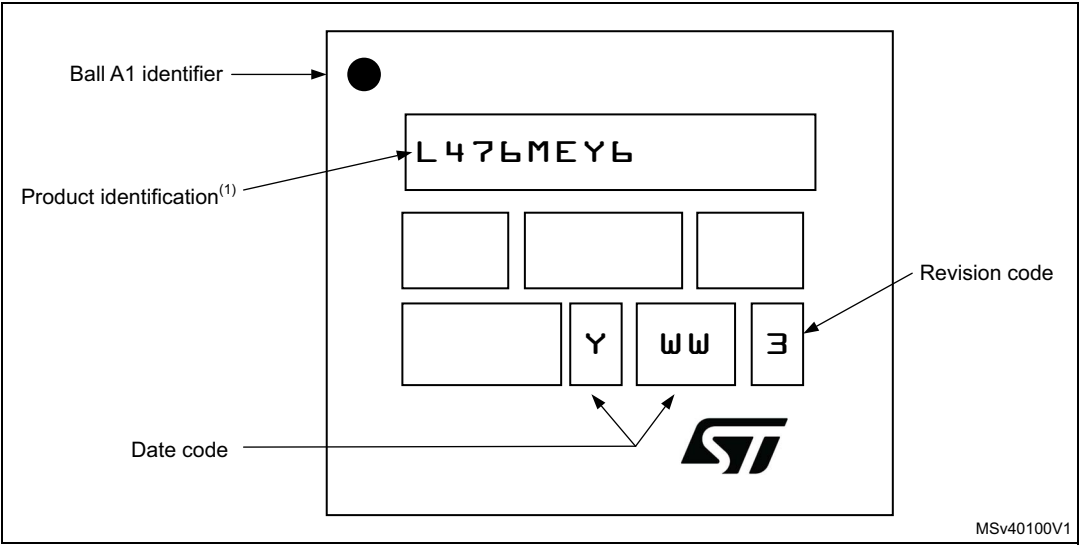
2. Guaranteed by characterization results.

Figure 39. Asynchronous multiplexed PSRAM/NOR read waveforms

Technical drawing of a square frame structure. The structure consists of four vertical columns and four horizontal beams. The columns are labeled with node numbers: 109 (top-left), 108 (top-right), 144 (bottom-left), and 37 (bottom-right). The beams are labeled with node numbers: 73 (top), 72 (right), 36 (bottom), and 1 (left). The dimensions are as follows: the overall width is 22.6, the overall height is 22.6, the horizontal beam length is 19.9, the vertical column height is 17.85, the horizontal beam thickness is 1.35, the vertical column thickness is 0.35, and the vertical column spacing is 0.5. The drawing is a black and white line drawing with dimensions and node numbers.

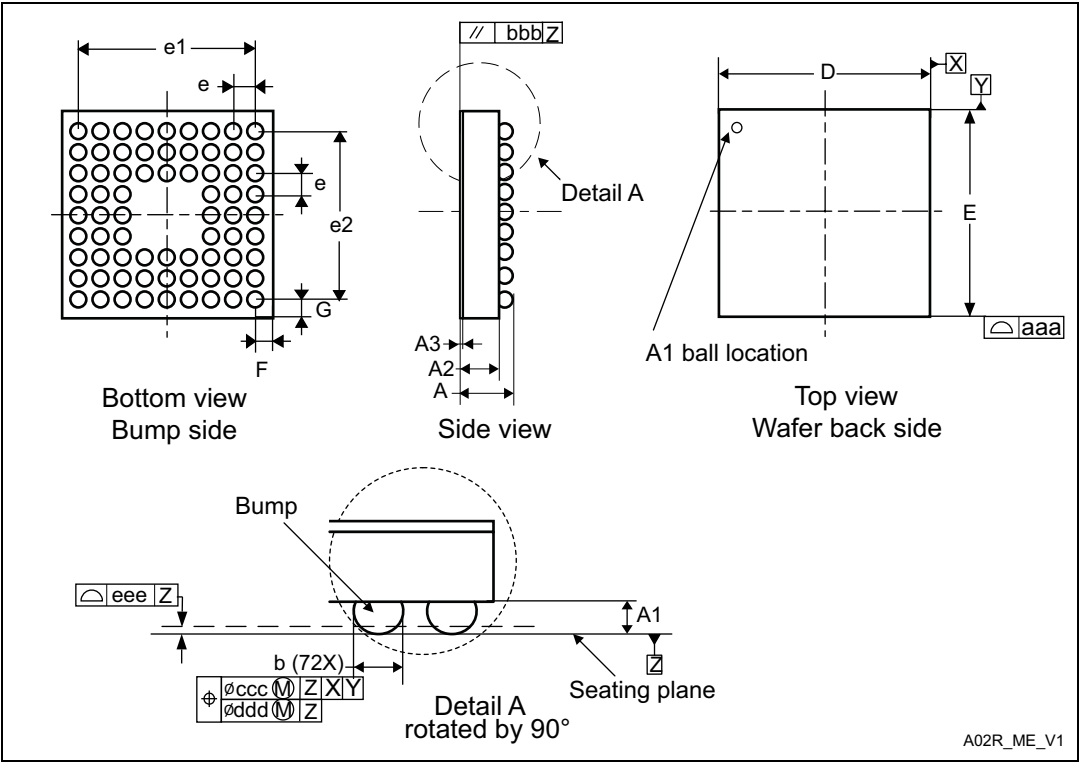
ai14905e

Figure 60. WLCSP81 marking (package top view)



7.5 WLCSP72 package information

Figure 61. WLCSP72 - 72-ball, 4.4084 x 3.7594 mm, 0.4 mm pitch wafer level chip scale package outline



1. Drawing is not to scale.

As applications do not commonly use the STM32L476xx at maximum dissipation, it is useful to calculate the exact power consumption and junction temperature to determine which temperature range will be best suited to the application.

The following examples show how to calculate the temperature range needed for a given application.

Example 1: High-performance application

Assuming the following application conditions:

Maximum ambient temperature $T_{Amax} = 82\text{ }^{\circ}\text{C}$ (measured according to JESD51-2),
 $I_{DDmax} = 50\text{ mA}$, $V_{DD} = 3.5\text{ V}$, maximum 20 I/Os used at the same time in output at low level with $I_{OL} = 8\text{ mA}$, $V_{OL} = 0.4\text{ V}$ and maximum 8 I/Os used at the same time in output at low level with $I_{OL} = 20\text{ mA}$, $V_{OL} = 1.3\text{ V}$

$$P_{INTmax} = 50\text{ mA} \times 3.5\text{ V} = 175\text{ mW}$$

$$P_{IOmax} = 20 \times 8\text{ mA} \times 0.4\text{ V} + 8 \times 20\text{ mA} \times 1.3\text{ V} = 272\text{ mW}$$

This gives: $P_{INTmax} = 175\text{ mW}$ and $P_{IOmax} = 272\text{ mW}$:

$$P_{Dmax} = 175 + 272 = 447\text{ mW}$$

Using the values obtained in [Table 113](#) T_{Jmax} is calculated as follows:

– For LQFP64, $45\text{ }^{\circ}\text{C/W}$

$$T_{Jmax} = 82\text{ }^{\circ}\text{C} + (45\text{ }^{\circ}\text{C/W} \times 447\text{ mW}) = 82\text{ }^{\circ}\text{C} + 20.115\text{ }^{\circ}\text{C} = 102.115\text{ }^{\circ}\text{C}$$

This is within the range of the suffix 6 version parts ($-40 < T_J < 105\text{ }^{\circ}\text{C}$) see [Section 8: Part numbering](#).

In this case, parts must be ordered at least with the temperature range suffix 6 (see Part numbering).

Note: *With this given P_{Dmax} we can find the T_{Amax} allowed for a given device temperature range (order code suffix 6 or 7).*

$$\text{Suffix 6: } T_{Amax} = T_{Jmax} - (45\text{ }^{\circ}\text{C/W} \times 447\text{ mW}) = 105 - 20.115 = 84.885\text{ }^{\circ}\text{C}$$

$$\text{Suffix 7: } T_{Amax} = T_{Jmax} - (45\text{ }^{\circ}\text{C/W} \times 447\text{ mW}) = 125 - 20.115 = 104.885\text{ }^{\circ}\text{C}$$

Example 2: High-temperature application

Using the same rules, it is possible to address applications that run at high ambient temperatures with a low dissipation, as long as junction temperature T_J remains within the specified range.

Assuming the following application conditions:

Maximum ambient temperature $T_{Amax} = 100\text{ }^{\circ}\text{C}$ (measured according to JESD51-2),
 $I_{DDmax} = 20\text{ mA}$, $V_{DD} = 3.5\text{ V}$, maximum 20 I/Os used at the same time in output at low level with $I_{OL} = 8\text{ mA}$, $V_{OL} = 0.4\text{ V}$

$$P_{INTmax} = 20\text{ mA} \times 3.5\text{ V} = 70\text{ mW}$$

$$P_{IOmax} = 20 \times 8\text{ mA} \times 0.4\text{ V} = 64\text{ mW}$$

This gives: $P_{INTmax} = 70\text{ mW}$ and $P_{IOmax} = 64\text{ mW}$:

$$P_{Dmax} = 70 + 64 = 134\text{ mW}$$

Thus: $P_{Dmax} = 134\text{ mW}$